

REFERENCES

1. Neagle, W., and Randell, D. R. (Eds.). (1989). Surface Analysis Techniques and Applications. Cambridge: Thomas Graham House.
2. Urban, M. W. (Ed.). (1996). Attenuated Total Reflectance Spectroscopy of Polymer: Theory and Practice. Washington, DC: American Chemical Society.
3. Harrick, N. J. (Ed.). (1979). Internal Reflection Spectroscopy. New York: Harrick Scientific Corporation.
4. Ekgasit, S., and Siesler, H. W. (1998). Simplified Equation for ATR Spectral Intensity of a Three-Phase System. Appl. Spectrosc., 52(3), 367-374.
5. Hansen, W. N. (Ed.). (1973). in Advance in Electrochemistry and Electrochemical Engineering. New York: John Wiley & Sons.
6. Hansen, W. N. (1965). Expanded formulas for attenuated total reflection and the derivation of absorption rules for single and multiple ATR spectrometer cells. Spectrochim. Acta, 21, 815-833.
7. Huang, J., and Urban, M. W. (1993). Novel Approach to Quantitative Depth Profiling of Surfaces Using ATR/FT-IR Measurements. Appl. Spectrosc., 47(7), 973-981.
8. Shick, R. A., Koenig, J. L., and Ishida, H. (1993). Theoretical Development for Depth Profiling of Stratified Layers Using Variable-Angle ATR. Appl. Spectrosc., 47(8), 1237-1244.
9. Ekgasit, S. (2000). ATR Spectral Intensity: What is the Upper Limit of Weak Absorption?. Appl. Spectrosc., 54, xxx. (Accepted for publication).
10. Hansen, W. N. (1968). Electric Fields Produced by the Propagation of Plane Coherent Electromagnetic Radiation in a Stratified Medium. J. Opt. Soc. Am., 58(3), 380-390.
11. Goplen, T. G., Cameron, D. G., and Jones, R. N. (1980). Absolute Absorption Intensity and Dispersion Measurements on Some Organic Liquids in the Infrared. Appl. Spectrosc., 34(6), 657-691.

12. Harrick, N. J. (1964). Multiple Reflection Cells for Internal Reflection Spectrometry. Anal. Chem., 36, 188-188.
13. Hirschfeld, T. (1967). Solution for the Sample Contact Problem in ATR. Appl. Spectrosc., 21(5), 335-336.
14. Ohta, K., and Iwamoto, R. (1985). Experimental Proof of the Relation Between Thickness of the Probed Surface Layer and Absorbance in FT-IR/ATR Spectroscopy. Appl. Spectrosc., 39(3), 418-425.
15. Ohta, K., and Iwamoto, R. (1985). Lower Limit of the Thickness of the Measurable Surface Layer by Fourier Transform Infrared Attenuated Total Reflection Spectrometry. Anal. Chem., 57, 2491-2499.
16. Iwamoto, R., and Ohta, K. (1984). Quantitative Surface Analysis by Fourier Transform Attenuated Total Reflection Infrared Spectroscopy. Appl. Spectrosc., 38(3), 359-365.
17. Hirschfeld, T. (1967). Solution for the Sample Contact Problem in ATR. Appl. Spectrosc., 21(5), 335-336.
18. Oelichmann, J. (1989). Surface and depth-profile analysis using FTIR spectroscopy. Fresenius Z Anal Chem. 333, 353-359.

CURRICULUM VITAE

Adchara Padermshoke



- 1976 Born December, 17th in Bangkok, Thailand
Father : Mr. Ittipol Padermshoke
Mother : Mrs. Sompat Padermshoke
- 1981 Elementary School (Songsermvidhaya School, Bangkok)
- 1983 Primary School (Songsermvidhaya School, Bangkok)
- 1989 High School (Samsenwittayalai School, Bangkok)
- 1994 Bachelor of Science (Chemistry),
Chulalongkorn University, Bangkok
- 1998 Master degree student at Faculty of Science,
Chulalongkorn University, Bangkok